

SKILL DEVELOPMENT WORKSHOP

Skill Development Workshop was organized by AIAE on **05—6 Oct, 2015**. The speakers namely Shri HN Ganesh, CTO and Sh S. Avinash, Director Innovent Engineering, Bangalore conducted the workshop.

Presentation on following topics was made:

1. Critical thinking in Engineering problems with case studies.
2. Lateral thinking in problem solving
3. Simulation methods using FEM
4. Thinking skill in cracking gate, M.Tech and other.

In competition a total of 168 students from AIAE, ASE, ASET (MAE) and ASET (Civil) and 12 faculties attended the program.

Photo collage may be referred. The visiting speakers called on VC and explained outline of proposed collaborative programme between AIAE and Innovent Engineering.

INTRODUCTION TO SKILL DEVELOPMENT WORKSHOP

There are reports that employability of Indian Engineering Graduates is poor. So in order to improve employability, our Government and the Prime Minister Mr Narendra Modi has laid emphasis on Skill Development of Engineering Graduates. As you all know that modeling analysis, simulation of any engineering product and system is essential tool to prove its efficacy, integrity and robust design. Our student should get exposure to skill development program in modeling and simulation-that is the objective of organizing this workshop.

We are organizing this workshop with experienced experts from Innovent Engineering. Innovent Engineering jointly with an international association of modeling, analysis, simulation called NAFEM undertakes certification of Engineers in field of CAE (Computer Aided Engineering).

It has international & national connectivity with NAFEM & NASSCOM. It is running several simulation programs in IISc and IITs.

The speakers namely Shri HN Ganesh CTO, Shri Avinash, Director, Shri Venkateshwaran CEO are all having international exposure with Rolls Royce, GE and HAL.

Apart from developing skills in modeling and simulation, they will devote one session on lateral and critical thinking how to crack GATE and other competition examinations.

